

Notice of References CitedApplication/Control No.
09/867,644Applicant(s)/Patent Under
Reexamination
JUANG ET AL.Examiner
A. SeferArt Unit
2826

Page 1 of 1

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	C	US-4,788,523	11-1988	Robins	338/309
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	U	Thomas et al. "Ti-Cu-Ni-Au (TCNA) compatibility with resistor and bilevel crossover circuit processing" (J. Vac. Sci. Technol., Vol. 13, No. 1, Jan/Feb. 1976).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.